

STN	Integrované obvody Meranie elektromagnetického vyžarovania Časť 8: Meranie vyžarovania Metóda IC páskových vedení	STN EN IEC 61967-8 35 8796
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Integrated circuits - Measurement of electromagnetic emissions - Part 8: Measurement of radiated emissions - IC stripline method

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 08/23

Obsahuje: EN IEC 61967-8:2023, IEC 61967-8:2023

Oznámením tejto normy sa od 07.06.2026 ruší
STN EN 61967-8 (35 8796) z marca 2012

137286



EUROPEAN STANDARD

EN IEC 61967-8

NORME EUROPÉENNE

EUROPÄISCHE NORM

June 2023

ICS 31.200

Supersedes EN 61967-8:2011

English Version

**Integrated circuits - Measurement of electromagnetic emissions -
Part 8: Measurement of radiated emissions - IC stripline method
(IEC 61967-8:2023)**

Circuits intégrés - Mesure des émissions
électromagnétiques - Partie 8: Mesure des émissions
rayonnées - Méthode de la ligne TEM à plaques (stripline)
pour circuit intégré
(IEC 61967-8:2023)

Integrierte Schaltungen - Messung von
elektromagnetischen Aussendungen - Teil 8: Messung der
abgestrahlten Aussendungen - IC-Streifenleiterverfahren
(IEC 61967-8:2023)

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Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 61967-8:2023 (E)

European foreword

The text of document 47A/1152/FDIS, future edition 2 of IEC 61967-8, prepared by SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61967-8:2023.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2024-03-07
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2026-06-07

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IEC 61967-2 NOTE Approved as EN 61967-2

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cencenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-131	-	International Electrotechnical Vocabulary - - Part 131: Circuit theory	-	-
IEC 60050-161	-	International Electrotechnical Vocabulary. - Chapter 161: Electromagnetic compatibility	-	-
IEC 61000-4-20	-	Electromagnetic compatibility (EMC) - Part 4-20: Testing and measurement techniques - Emission and immunity testing in transverse electromagnetic (TEM) waveguides	EN IEC 61000-4-20 -	-
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions - Part 1: General conditions and definitions	EN IEC 61967-1	-



IEC 61967-8

Edition 2.0 2023-05

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Integrated circuits – Measurement of electromagnetic emissions –
Part 8: Measurement of radiated emissions – IC stripline method**

**Circuits intégrés – Mesure des émissions électromagnétiques –
Partie 8: Mesure des émissions rayonnées – Méthode de la ligne TEM à plaques
(stripline) pour circuit intégré**



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IEC 61967-8

Edition 2.0 2023-05

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Integrated circuits – Measurement of electromagnetic emissions –
Part 8: Measurement of radiated emissions – IC stripline method**

**Circuits intégrés – Mesure des émissions électromagnétiques –
Partie 8: Mesure des émissions rayonnées – Méthode de la ligne TEM à plaques
(stripline) pour circuit intégré**

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ICS 31.200

ISBN 978-2-8322-6932-9

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –

Part 8: Measurement of radiated emissions – IC stripline method

FOREWORD

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IEC 61967-8 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices. It is an International Standard.

This second edition cancels and replaces the first edition published in 2011. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) frequency range of 150 kHz to 3 GHz was deleted from the scope;
- b) extension of upper usable frequency to 6 GHz or higher as long as the defined requirements are fulfilled.

The text of this International Standard is based on the following documents:

Draft	Report on voting
47A/1152/FDIS	47A/1153/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts of the IEC 61967 series, under the general title *Integrated circuits – Measurement of electromagnetic emissions* can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

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INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –

Part 8: Measurement of radiated emissions – IC stripline method

1 Scope

This part of IEC 61967 defines a method for measuring the electromagnetic radiated emission from an integrated circuit (IC) using an IC stripline. The IC being evaluated is mounted on an EMC test board (PCB) between the active conductor and the ground plane of the IC stripline arrangement.

2 Normative references

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